



13th Biennial Conference on High Resolution X-Ray Diffraction and Imaging

XTOP 2016

Methods and techniques:

- High resolution diffraction and topography
- X-ray reflectometry and small-angle scattering
- Microdiffraction and nanodiffraction
- Coherent diffraction imaging
- Absorption and phase contrast imaging and tomography
- Resonant (anomalous) scattering
- Fluorescence imaging
- Time resolved methods
- Theory and simulations of X-ray scattering

Applications:

- Material science (from 0D to 3D objects)
- Nanomaterials and nanoscience
- Life and environmental sciences
- Non-destructive testing (including industrial needs and cultural heritage)

Instrumentation:

- X-ray optics and instrumentation
- Advances in laboratory instrumentation and applications
- Advances in synchrotron instrumentation and applications
- Experiments at X-ray free-electron lasers

Scientific advisory board:

Václav Holý (chairman), José Baruchel, Dina Carbone, Alessia Cedola, Jaroslav Domagala, Vincent Favre-Nicolin, Paul Fewster, Jorg Grenzer, Ullrich Pietsch, Tobias Schüll, Julian Stangl, Brian Tanner, Pam Thomas, Alex Ulyanenko, Emil Zolotoyabko

Organizing committee:

Petr Mikulík (chairman), Ondřej Čaha, Radomír Kužel, Mojmír Meduňa, Jiří Novák, Jakub Rozbořil

Organizing institutions:

Masaryk University, Brno
CSCA – Czech and Slovak Crystallographic Association
CEITEC – Central European Institute of Technology, Brno



4th – 8th September 2016
Brno, Czech Republic

<http://xtop2016.sci.muni.cz>

Tutorial lectures on the first conference day:

José Baruchel, Stefan Carlson,
Ana Diaz, Cinzia Giannini,
Cristian Mocuta, Sverker Werin

Invited speakers:

Federico Boscherini, Virginie Chamard,
Semën Gorfman, Jan Philipp Hofmann,
Jozef Keckes, Julian Moosmann,
Tim Salditt, Paolo Scardi,
Andreas Stierle, Igor Zlotnikov,
Marvin Zoellner

